

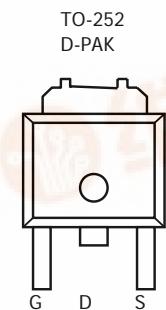


ALPHA & OMEGA
SEMICONDUCTOR, LTD.

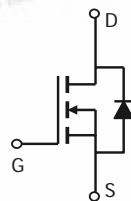
Rev3: Nov 2004

AOD410, AOD410L (Green Product) N-Channel Enhancement Mode Field Effect Transistor

General Description	Features
<p>The AOD410 uses advanced trench technology to provide excellent $R_{DS(ON)}$ and low gate charge. This device is suitable for use as a load switch or in PWM applications. AOD410L (Green Product) is offered in a lead-free package.</p>	<p>$V_{DS} (V) = 30V$ $I_D = 8A$ $R_{DS(ON)} < 65m\Omega (V_{GS} = 10V)$ $R_{DS(ON)} < 105m\Omega (V_{GS} = 4.5V)$</p>



Top View
Drain Connected to Tab



Absolute Maximum Ratings $T_A=25^\circ C$ unless otherwise noted

Parameter	Symbol	Maximum	Units
Drain-Source Voltage	V_{DS}	30	V
Gate-Source Voltage	V_{GS}	± 20	V
Continuous Drain Current ^G	I_D	8	A
$T_C=100^\circ C$		6	
Pulsed Drain Current ^B	I_{DM}	20	
Avalanche Current ^C	I_{AR}	8	A
Repetitive avalanche energy $L=0.1mH$ ^C	E_{AR}	10	mJ
Power Dissipation ^B	P_D	25	W
$T_C=100^\circ C$		12.5	
Power Dissipation ^A	P_{DSM}	2.1	W
$T_A=70^\circ C$		1.33	
Junction and Storage Temperature Range	T_J, T_{STG}	-55 to 175	°C

Thermal Characteristics

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient ^A	$R_{\theta JA}$	20	30	°C/W
Maximum Junction-to-Ambient ^A		46	60	°C/W
Maximum Junction-to-Case ^C	$R_{\theta JL}$	5.3	7	°C/W

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Electrical Characteristics ($T_J=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
STATIC PARAMETERS						
BV_{DSS}	Drain-Source Breakdown Voltage	$I_D=250\mu\text{A}, V_{GS}=0\text{V}$	30			V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=24\text{V}, V_{GS}=0\text{V}$ $T_J=55^\circ\text{C}$		1	5	μA
I_{GSS}	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS} = \pm 20\text{V}$		100	100	nA
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$	1	1.8	3	V
$I_{D(\text{ON})}$	On state drain current	$V_{GS}=4.5\text{V}, V_{DS}=5\text{V}$	10			A
$R_{DS(\text{ON})}$	Static Drain-Source On-Resistance	$V_{GS}=10\text{V}, I_D=8\text{A}$ $T_J=125^\circ\text{C}$	48	65		$\text{m}\Omega$
		$V_{GS}=4.5\text{V}, I_D=2\text{A}$	76	100		$\text{m}\Omega$
g_{FS}	Forward Transconductance	$V_{DS}=5\text{V}, I_D=8\text{A}$		6.2		S
V_{SD}	Diode Forward Voltage	$I_S=1\text{A}, V_{GS}=0\text{V}$		0.75	1	V
I_S	Maximum Body-Diode Continuous Current			4.3		A
DYNAMIC PARAMETERS						
C_{iss}	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=15\text{V}, f=1\text{MHz}$		288		pF
C_{oss}	Output Capacitance			57		pF
C_{rss}	Reverse Transfer Capacitance			39		pF
R_g	Gate resistance	$V_{GS}=0\text{V}, V_{DS}=0\text{V}, f=1\text{MHz}$		3		Ω
SWITCHING PARAMETERS						
$Q_g(10\text{V})$	Total Gate Charge	$V_{GS}=10\text{V}, V_{DS}=15\text{V}, I_D=8\text{A}$		6.72		nC
$Q_g(4.5\text{V})$	Total Gate Charge			3.34		nC
Q_{gs}	Gate Source Charge			0.76		nC
Q_{gd}	Gate Drain Charge			1.78		nC
$t_{D(\text{on})}$	Turn-On DelayTime	$V_{GS}=10\text{V}, V_{DS}=15\text{V}, R_L=1.8\Omega, R_{\text{GEN}}=3\Omega$		3.7		ns
t_r	Turn-On Rise Time			3.7		ns
$t_{D(\text{off})}$	Turn-Off DelayTime			15.6		ns
t_f	Turn-Off Fall Time			2.6		ns
t_{rr}	Body Diode Reverse Recovery Time	$I_F=8\text{A}, dI/dt=100\text{A}/\mu\text{s}$		12.6		ns
Q_{rr}	Body Diode Reverse Recovery Charge	$I_F=8\text{A}, dI/dt=100\text{A}/\mu\text{s}$		5.1		nC

A: The value of R_{JJA} is measured with the device mounted on 1 in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{C}$. The Power dissipation P_{DSM} is based on R_{JJA} and the maximum allowed junction temperature of 150°C. The value in any given application depends on the user's specific board design, and the maximum temperature to 175°C may be used if the PCB allows it.

B. The power dissipation P_0 is based on $T_{J(\text{MAX})}=175^\circ\text{C}$, using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.

C: Repetitive rating, pulse width limited by junction temperature $T_{J(\text{MAX})}=175^\circ\text{C}$.

D. The R_{JJA} is the sum of the thermal impedance from junction to case R_{JJC} and case to ambient.

E. The static characteristics in Figures 1 to 6 are obtained using <300 μs pulses, duty cycle 0.5% max.

F. These tests are performed with the device mounted on 1 in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{C}$. The SOA curve provides a single pulse rating.

G. The maximum current rating is limited by bond-wires.

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TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

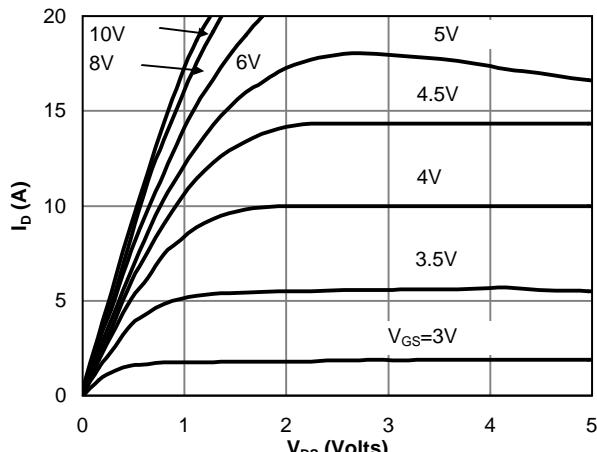


Fig 1: On-Region Characteristics

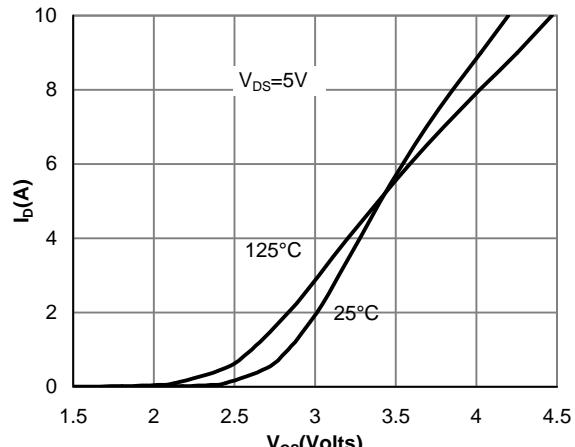


Figure 2: Transfer Characteristics

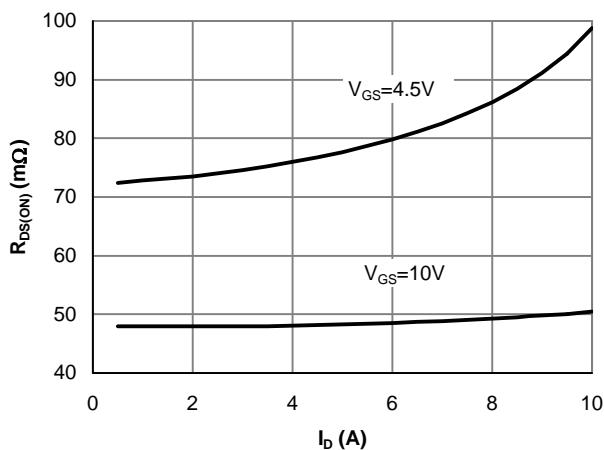


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

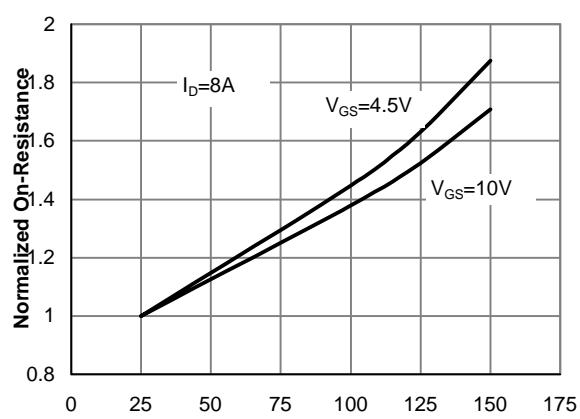


Figure 4: On-Resistance vs. Junction Temperature

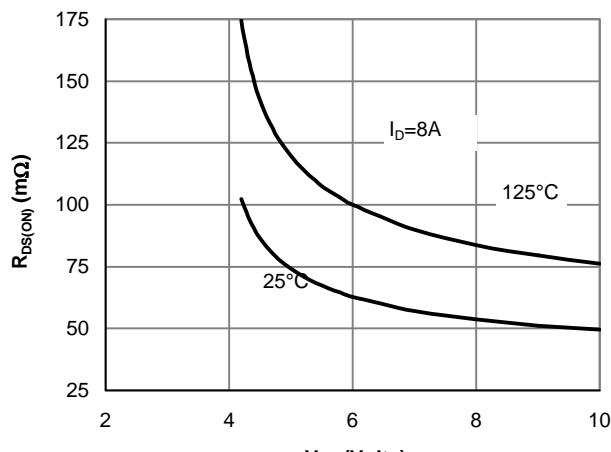


Figure 5: On-Resistance vs. Gate-Source Voltage

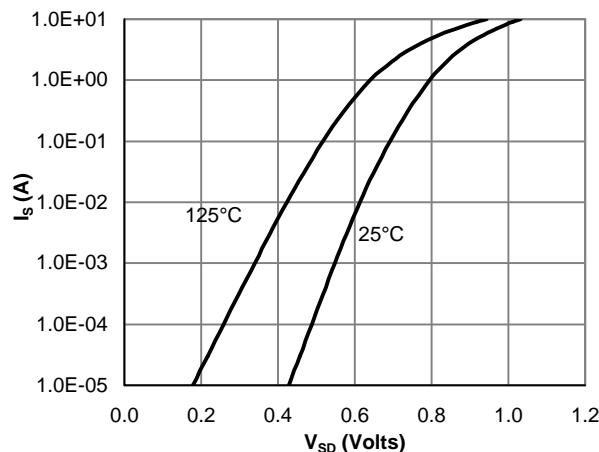


Figure 6: Body-Diode Characteristics

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TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

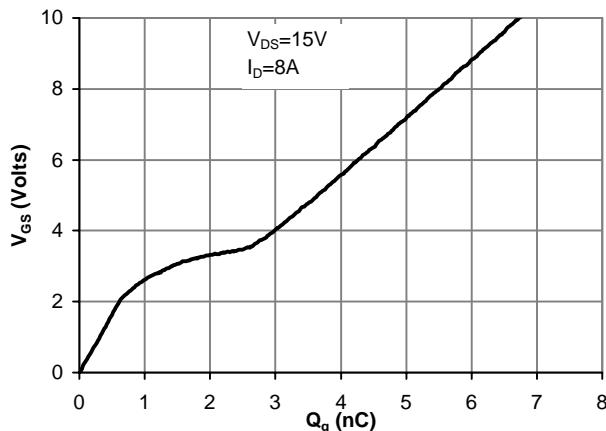


Figure 7: Gate-Charge Characteristics

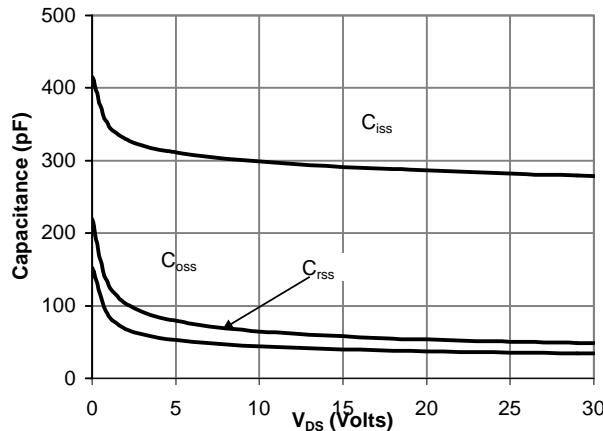


Figure 8: Capacitance Characteristics

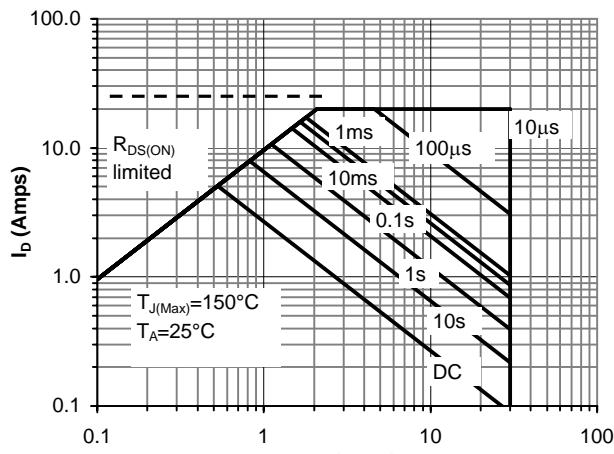


Figure 9: Maximum Forward Biased Safe Operating Area (Note F)

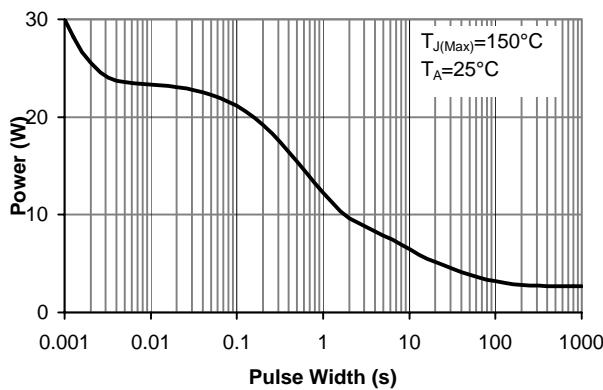


Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note F)

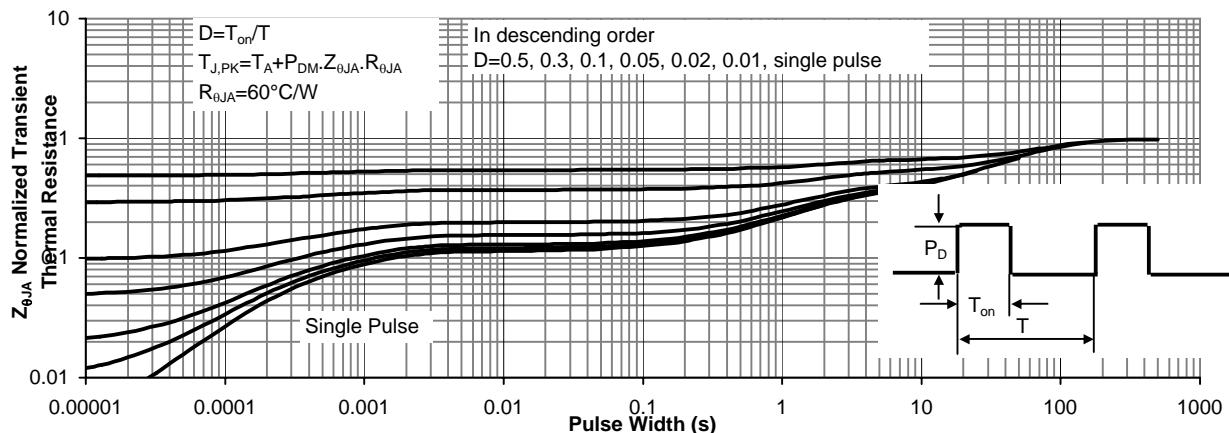


Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)